Notice of References Cited Application/Control No. 10/617,015 Examiner JASON M. GARR Applicant(s)/Patent Under Reexamination CHEN, YINGJIAN Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,430,511 B1	08-2002	Tour et al.	702/19
*	В	US-2003/0142440 A1	07-2003	Clinton et al.	360/123
*	С	US-2003/0123189 A1	07-2003	Sato et al.	360/234.5
*	D	US-2004/0214367 A1	10-2004	Segal et al.	438/053
*	Е	US-2004/0201930 A1	10-2004	Yoshikawa et al.	360/324.1
*	F	US-2004/0264064 A1	12-2004	Sakakima, Hiroshi	360/322
*	G	US-6,828,039 B2	12-2004	Sugawara, Takahiko	428/621
*	Ι	US-6,833,980 B1	12-2004	Tsukagoshi et al.	360/324
*	I	US-2005/0068679 A1	03-2005	Chen, Ga-Lane	360/131
*	J	US-6,917,493 B2	07-2005	Clinton et al.	360/125.02
*	K	US-6,920,014 B2	07-2005	Sato et al.	360/234.5
*	L	US-2006/0092542 A1	05-2006	Ushida et al.	360/059
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2004221442 A	08-2004	Japan	SUGAWARA, TAKAHIKO	H01L 43/08
	0					
	Р					
	Q					
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	W	
	×	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.